

GL Silicon N-Channel Power MOSFET
General Description:

The GL1S50N06LA3 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is TO-251, which accords with the RoHS standard.

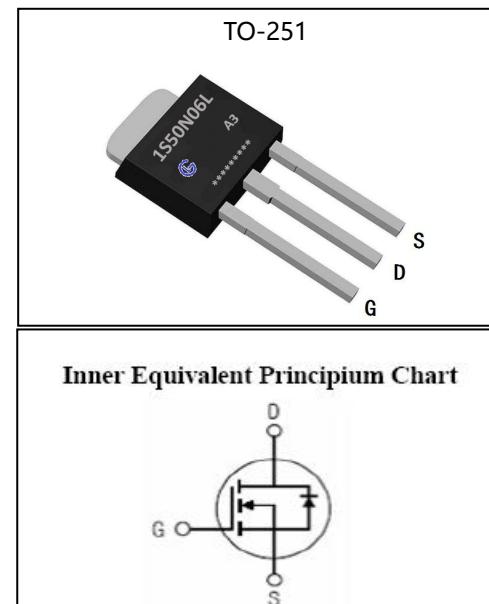
V _{DSS}	60	V
I _D	50	A
P _D	85	W
R _{DS(ON)type}	13.5	mΩ

Features:

- Fast Switching
- Low Gate Charge and R_{dson}
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

Applications:

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply


Absolute (T_c = 25°C unless otherwise specified):

Symbol	Parameter	Rating	Units
V _{DSS}	Drain-to-Source Voltage	60	V
I _D	Continuous Drain Current	50	A
	Continuous Drain Current T _C = 100 °C	35	A
I _{DM}	Pulsed Drain Current	200	A
V _{GS}	Gate-to-Source Voltage	±20	V
E _{AS} ^{a2}	Single Pulse Avalanche Energy	300	mJ
E _{AR} ^{a1}	Avalanche Energy ,Repetitive	50	mJ
I _{AR} ^{a1}	Avalanche Current	28	A
dv/dt ^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P _D	Power Dissipation	85	W
T _J , T _{stg}	Operating Junction and Storage Temperature Range	175, -55 to 175	°C
T _L	MaximumTemperature for Soldering	300	°C



GL1S50N06LA3

GL Silicon N-Channel Power MOSFET

Electrical Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	60	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu\text{A}$, Reference 25°C	--	0.1	--	$\text{V}/^\circ\text{C}$
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=60\text{V}, V_{GS}=0\text{V}, T_a=25^\circ\text{C}$	--	--	1	μA
		$V_{DS}=48\text{V}, V_{GS}=0\text{V}, T_a=125^\circ\text{C}$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+20\text{V}$	--	--	1	μA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-20\text{V}$	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$	--	13.5	18	$\text{m}\Omega$
$V_{GS(\text{TH})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.0	--	2.5	V
Pulse width $t_p \leq 380\mu\text{s}, \delta \leq 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$	18	--	--	S
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=30\text{V}$	--	2050	--	pF
C_{oss}	Output Capacitance	$f=1.0\text{MHz}$	--	158	--	
C_{rss}	Reverse Transfer Capacitance		--	120	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time		--	7.5	--	ns
t_r	Rise Time	$I_D=20\text{A}, V_{DD}=30\text{V}$	--	5.0	--	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS}=10\text{V}, R_G=3.0\Omega$	--	28.0	--	
t_f	Fall Time		--	5.5	--	
Q_g	Total Gate Charge	$I_D=20\text{A}, V_{DD}=30\text{V}$	--	50	--	nC
Q_{gs}	Gate to Source Charge	$V_{GS}=10\text{V}$	--	6	--	
Q_{gd}	Gate to Drain ("Miller")Charge		--	15	--	

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Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	50	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	200	A
V_{SD}	Diode Forward Voltage	$I_S=50A, V_{GS}=0V$	--	--	1.5	V
t_{rr}	Reverse Recovery Time	$I_S=20A, T_j = 25^\circ C$	--	30	--	ns
Q_{rr}	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	40	--	nC
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Symbol	Parameter	Typ.	Units
$R_{\theta JA}$	Junction-to-Ambient	1.8	°C/W

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: EAS condition : $T_j=25^\circ C, V_{DD}=30V, V_G=10V, L=0.5mH, R_g=25\Omega$

^{a3}: $I_{SD} = 20A, dI/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_j=25^\circ C$

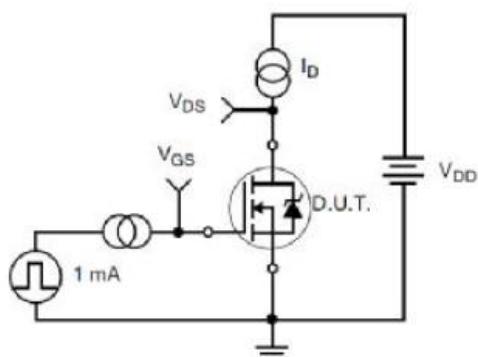
Test Circuit and Waveform


Figure 17. Gate Charge Test Circuit

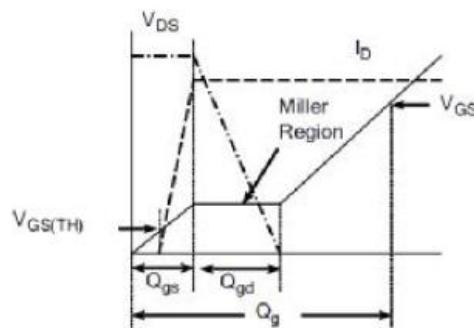


Figure 18. Gate Charge Waveform

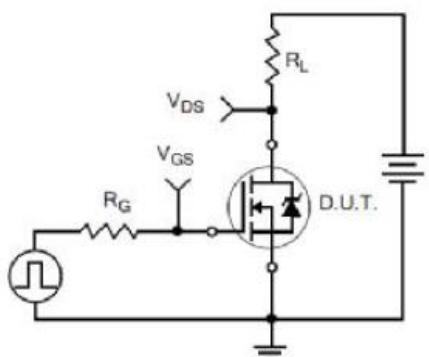


Figure 19. Resistive Switching Test Circuit

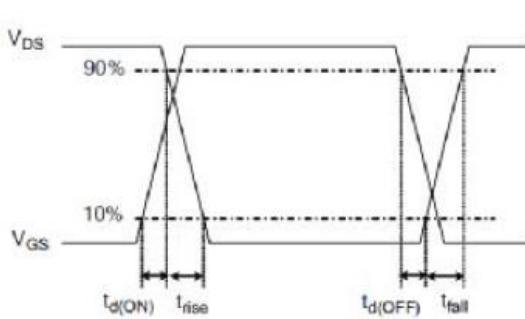
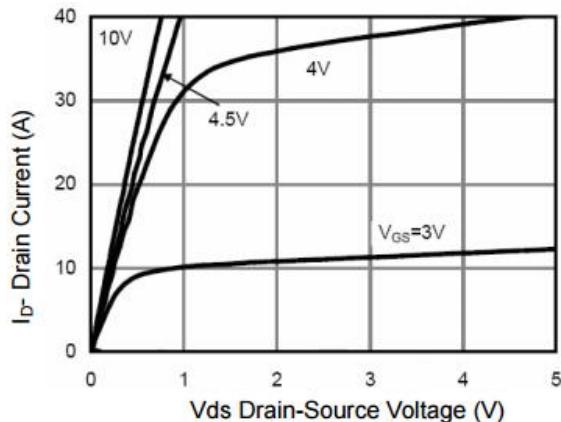
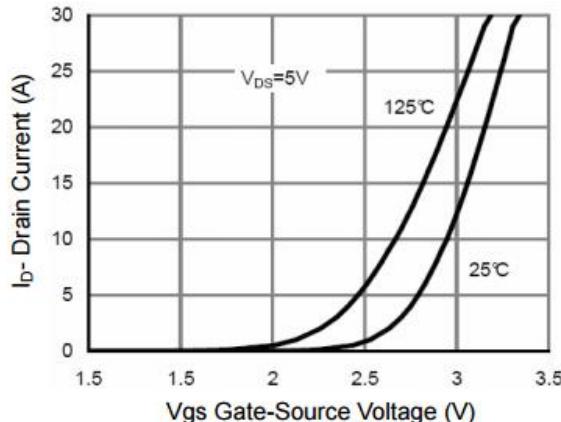
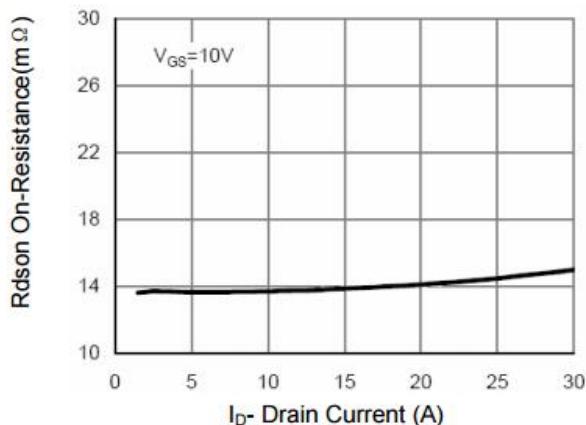
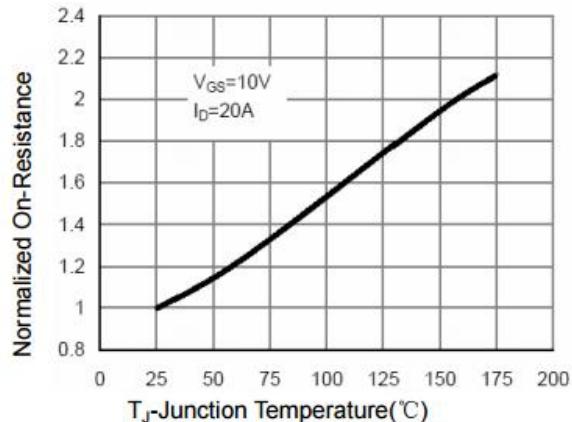
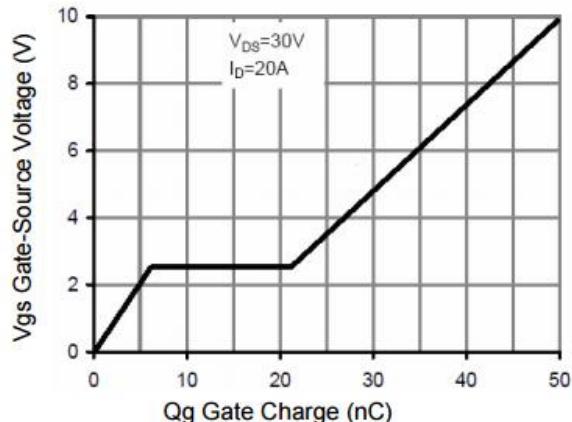
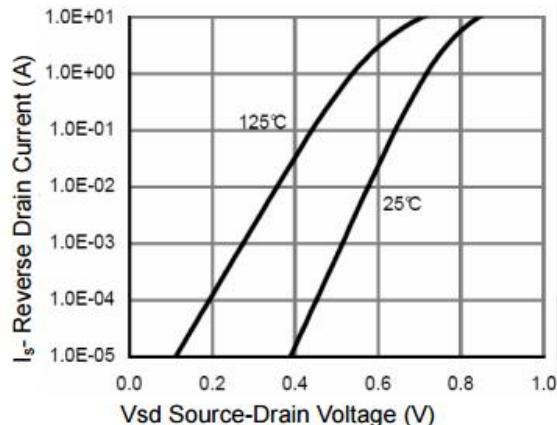
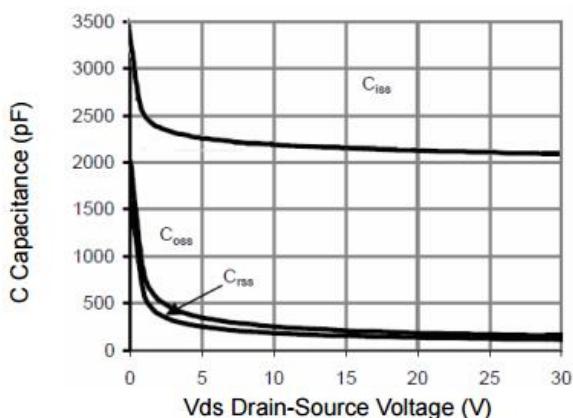
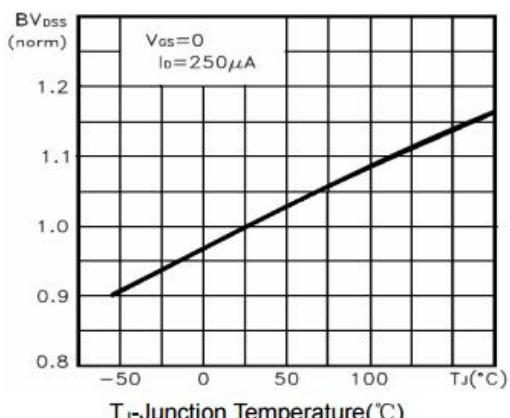
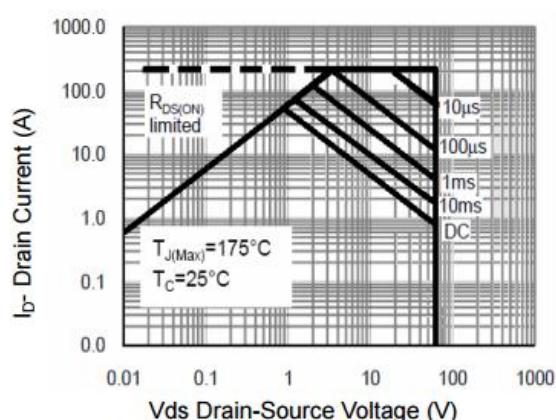
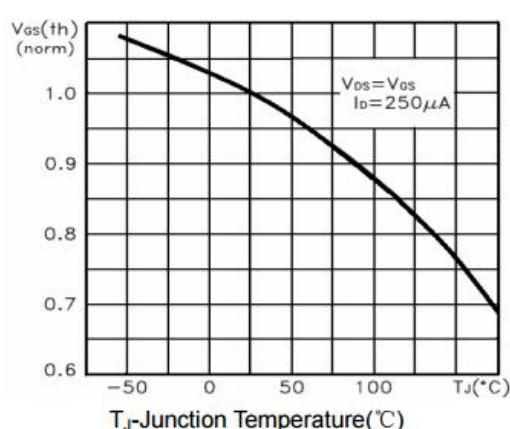
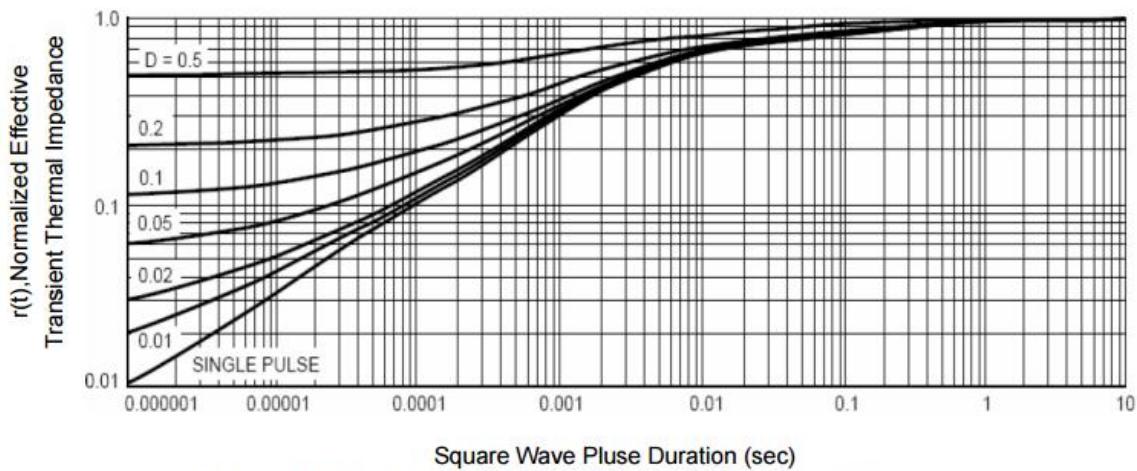


Figure 20. Resistive Switching Waveforms

Characteristics Curve:

Figure 1 Output Characteristics

Figure 2 Transfer Characteristics

Figure 3 Rdson- Drain Current

Figure 4 Rdson-Junction Temperature

Figure 5 Gate Charge

Figure 6 Source- Drain Diode Forward

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Figure 7 Capacitance vs Vds

Figure 9 BV_{DSS} vs Junction Temperature

Figure 8 Safe Operation Area

Figure 10 $V_{GS(\text{th})}$ vs Junction Temperature

Figure 11 Normalized Maximum Transient Thermal Impedance